

Notice of References Cited

Application/Control No.	09/661,806	Applicant(s)/Patent Under Reexamination HASEGAWA ET AL.
Examiner	Art Unit Sunray Chang	2123 Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,363,169 B1	03-2002	Ritter et al.	382/154
B	US-4,910,611	03-1990	Cok, David R.	358/453
C	US-6,343,987 B2	02-2002	Hayama et al.	463/1
D	US-6,549,202 B1	04-2003	Hasegawa et al.	345/426
E	US-6,603,479 B1	08-2003	Mifune et al.	345/474
F	US-6,549,288 B1	04-2003	Migdal et al.	356/603
G	US-6,281,902 B1	08-2001	Nagashima, Hiroshi	345/419
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

